



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

JAMES BROC STIRTON

Serial No.: 09/824,156

Filed: April 2, 2001

For:

Sir:

METHOD OF MEASURING IMPLANT

PROFILES USING

Assistant Commissioner for Patents

Washington, D.C. 20231

SCATTEROMETRIC TECHNIQUES

Group Art Unit: 2877

Examiner: Juan D. Valentin

Atty. Dkt. No.: 2000.071000/TT4354

RESPONSE TO OFFICE ACTION DATED JANUARY 2, 2003

CERTIFICATE OF MAILING 37 C.F.R 1.8

I hereby certify that this correspondence is being deposited with the U.S. Postal Service with sufficient postage as First Class Mail in an envelope addressed to: Assistant Commissioner for Patents, Washington, D.C. 20231, on the date below:

March 21, 2003

Date

This paper is submitted in response to the Office Action dated January 2, 2003 for which the three-month date for response is April 2, 2003.

No fee is believed to be due in connection with the present paper. However, should any fees be required, the Assistant Commissioner is authorized to deduct any fees required under 37 C.F.R. §§ 1.16 to 1.21 from the Advanced Micro Devices, Inc. Deposit Account No. 01-0365/TT4354. In the event the monies in that account are insufficient, the Assistant Commissioner is authorized to withdraw funds from Williams, Morgan & Amerson, P.C. Deposit Account No. 50-0786/2000.071000.

Reconsideration of the application in view of the following remarks is respectfully requested.

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